



Paper No. 5

BROWN RAYSMAN MILLSTEIN  
FELDER & STEINER  
120 WEST 45TH STREET  
NEW YORK, NY 10036

**COPY MAILED**

**FEB 27 2001**

In re Application of  
Ly, Macmillen, Miller & Knapp  
Application No. 09/590,584  
Filed: June 8, 2000  
Attorney Docket No. 4000/10  
For: METHODS FOR AUTOMATICALLY  
PIPELINING LOOPS

: OFFICE OF PETITIONS  
: A/C PATENTS  
: DECISION ACCORDING STATUS  
: UNDER 37 CFR 1.47(a)  
:  
:

This is in response to the "Petition Under 37 CFR 1.47(a)," filed October 16, 2000.

The petition is **granted**.

Petitioner has shown that the non-signing inventor, Mr. David W. Knapp, has refused to join in the filing of the above-identified application after having been presented with the application papers. Specifically, the declaration of Jonathan T. Kaplan, an attorney of record, establishes that the non-signing inventor was mailed a complete copy of the application papers, including the specification, claims and drawings, but refused in writing to sign the declaration.

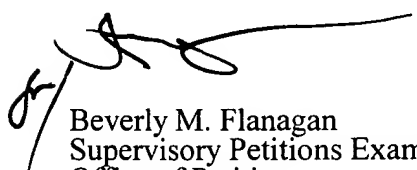
The above-identified application and papers have been reviewed and found in compliance with 37 CFR 1.47(a). This application is hereby accorded Rule 1.47(a) status.

As provided in Rule 1.47(a), this Office will forward notice of this application's filing to the non-signing inventor at the address given in the petition. Notice of the filing of this application will also be published in the Official Gazette.

Pursuant to petitioners' authorization, deposit account no. 02-4270 was charged \$110.00 for the one month extension of time, \$130.00 for filing a late declaration, and \$130.00 for filing the instant petition to the Commissioner.

After this decision is mailed, the above-identified application will be forwarded to the Office of Initial Patent Examination for issuance of a corrected filing receipt.

Telephone inquiries should be directed to Petitions Attorney E. Shirene Willis at (703) 308-6712.

  
Beverly M. Flanagan  
Supervisory Petitions Examiner  
Office of Petitions  
Office of the Deputy Commissioner  
for Patent Examination Policy